

1. Record Nr.	UNINA9910131030003321
Titolo	Surface and thin film analysis [[electronic resource]] : a compendium of principles, instrumentation, and applications // edited by Gernot Friedbacher and Henning Bubert
Pubbl/distr/stampa	Weinheim, Germany, : Wiley-VCH, 2011
ISBN	1-283-14094-2 9786613140944 3-527-63694-3 3-527-63692-7
Edizione	[2nd ed.]
Descrizione fisica	1 online resource (559 p.)
Altri autori (Persone)	FriedbacherGernot BubertH (Henning)
Disciplina	530.4275 541.33
Soggetti	Thin films - Surfaces - Analysis Electron spectroscopy Spectrum analysis Pel·lícules fines Espectroscòpia d'electrons Llibres electrònics
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	pt. 1. Electron detection -- pt. 2. Ion detection -- pt. 3. Photon detection -- pt. 4. Scanning probe microscopy.
Sommario/riassunto	Surveying and comparing all techniques relevant for practical applications in surface and thin film analysis, this second edition of a bestseller is a vital guide to this hot topic in nano- and surface technology. This new book has been revised and updated and is divided into four parts - electron, ion, and photon detection, as well as scanning probe microscopy. New chapters have been added to cover such techniques as SNOM, FIM, atom probe (AP), and sum frequency generation (SFG). Appendices with a summary and comparison of techniques and a list of equipment suppliers make this book a rapid ref

